SLOVENSKI STANDARD
SIST ISO 5725-2:2003/C1:2003

01-junij-2003

Točnost (pravilnost in natančnost) merilnih metod in rezultatov – 2. del : Temeljna metoda določanja ponovljivosti in obnovljivosti standardne merilne metode ; tehnični popravek 1

Accuracy (trueness and precision) of measurement methods and results -- Part 2: Basic method for the determination of repeatability and reproducibility of a standard measurement method

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Ta slovenski standard je istoveten z: ISO 5725-2:1994/Cor 1:2002

ICS:

03.120.30	Uporaba statističnih metod	Application of statistical methods
17.020	Meroslovje in merjenje na splošno	Metrology and measurement in general

SIST ISO 5725-2:2003/C1:2003 en

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SIST ISO 5725-2:2003/C1:2003

INTERNATIONAL STANDARD ISO 5725-2:1994
TECHNICAL CORRIGENDUM 1

Published 2002-05-15

INTERNATIONAL ORGANIZATION FOR STANDARDIZATION • МЕЖДУНАРОДНАЯ ОРГАНИЗАЦИЯ ПО СТАНДАРТИЗАЦИИ • ORGANISATION INTERNATIONALE DE NORMALISATION

Accuracy (trueness and precision) of measurement methods and results —

Part 2:
Basic method for the determination of repeatability and reproducibility of a standard measurement method

TECHNICAL CORRIGENDUM 1

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RECTIFICATIF TECHNIQUE 1

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Technical Corrigendum 1 to International Standard ISO 5725-2:1994 was prepared by Technical Committee ISO/TC 69, *Applications of statistical methods*, Subcommittee SC 6, *Measurement methods and results.*

Page 12, subclause 7.3.4.3

Add the following note at the end of the subclause 7.3.4.3:

> "NOTE According to 7.3.2.1, an item is to be called a statistical outlier if the test statistic is greater than its 1 % critical value. When the Grubbs' test is first applied to a group of cell means, a critical value from Table 5 is used to test the highest cell mean using a test at the 0,5 % level, and to test the lowest cell mean at the 0,5 % level. This amounts to a test of the most extreme cell mean at the 1 % level in accordance with 7.3.2.1. If the most extreme cell mean is found to be a statistical outlier, the Grubbs' test is then applied to the other extreme cell mean. It can be argued that a one-sided test should now be used. However, the procedure recommended in this part of ISO 5725 is to use only the critical values tabulated in Table 5 (the critical values for two-sided tests at the 1 % significance level) in order that all cell means be treated consistently. A similar argument may be used to justify the use of the two-sided 5 % critical values in Table 5 for all tests for statistical stragglers."

ICS 03.120.30 **Ref. No. ISO 5725-2:1994/Cor.1:2002(E)**

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Printed in Switzerland

SIST ISO 5725-2:2003/C1:2003

Page 22, Table 5

Add the following note at the end of Table 5:

"NOTE The critical values given in this table are appropriate when two-sided tests are required. They are the critical values required by the procedure for applying the Grubbs' outlier tests described in 7.3.4 of this part of ISO 5725. They have been derived from the critical values for the corresponding one-sided tests as given in reference [4] of annex C."

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